

# TSK80R380S1

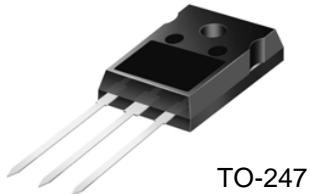
## 800V 13.6A N-Channel SJ-MOSFET

### General Description

Truesemi SJ-FET is new generation of high voltage MOSFET family that is utilizing an advanced charge balance mechanism for outstanding low on-resistance and lower gate charge performance.

This advanced technology has been tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy.

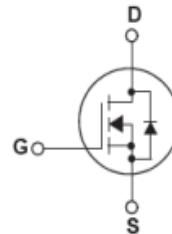
SJ-FET is suitable for various AC/DC power conversion in switching mode operation for higher efficiency.



TO-247

### Features

- 850V @ $T_J = 150\text{ }^{\circ}\text{C}$
- Typ.  $R_{DS(on)} = 0.34\Omega$
- Ultra Low gate charge (typ.  $Q_g = 17.5\text{nC}$ )
- 100% avalanche tested



### Absolute Maximum Ratings

Symbol	Parameter	Value	Unit
$V_{DSS}$	Drain-Source Voltage	800	V
$I_D$	Drain Current -Continuous ( $TC = 25\text{ }^{\circ}\text{C}$ )	13.6*	A
	-Continuous ( $TC = 100\text{ }^{\circ}\text{C}$ )	8.6*	
$I_{DM}$	Drain Current – Pulsed (Note 1)	40	A
$V_{GSS}$	Gate-Source voltage	$\pm 30$	V
$E_{AS}$	Single Pulsed Avalanche Energy (Note 2)	284	mJ
$I_{AR}$	Avalanche Current (Note 1)	2.4	A
$E_{AR}$	Repetitive Avalanche Energy (Note 1)	0.43	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$ (Note 3)	15	V/ns
$P_D$	Power Dissipation ( $TC = 25\text{ }^{\circ}\text{C}$ )	104	W
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^{\circ}\text{C}$
$T_L$	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	300	$^{\circ}\text{C}$

\* Drain current limited by maximum junction temperature.

### Thermal Characteristics

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.2	$^{\circ}\text{C}/\text{W}$
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink Typ.	0.5	$^{\circ}\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62	$^{\circ}\text{C}/\text{W}$

**Electrical Characteristics TC = 25°C unless otherwise noted**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Off Characteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA, T <sub>J</sub> = 25°C	800	--	--	V
		V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA, T <sub>J</sub> = 150°C	--	850	--	V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250µA, Referenced to 25°C	--	0.6	--	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 800V, V <sub>GS</sub> = 0V -T <sub>J</sub> = 150°C	--	-- 10	1 --	µA µA
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30V, V <sub>DS</sub> = 0V	--	--	100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30V, V <sub>DS</sub> = 0V	--	--	-100	nA
On Characteristics						
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250µA	2.5	3.5	4.5	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 7.5A	--	0.34	0.38	Ω
g <sub>FS</sub>	Forward Trans conductance	V <sub>DS</sub> = 40V, I <sub>D</sub> = 15A	--	12	--	S
R <sub>g</sub>	Gate resistance	f=1MHz,open drain	--	3.5	--	Ω
Dynamic Characteristics						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V, f = 1.0MHz	--	800	--	pF
C <sub>oss</sub>	Output Capacitance		--	230	--	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		--	15	--	pF
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 400V, I <sub>D</sub> = 7.5A R <sub>G</sub> = 20Ω(Note 4)	--	31	--	ns
t <sub>r</sub>	Turn-On Rise Time		--	19	--	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		--	91	--	ns
t <sub>f</sub>	Turn-Off Fall Time		--	20	--	ns
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = 480V, I <sub>D</sub> = 7.5A V <sub>GS</sub> = 10V (Note 4)	--	17.5	--	nC
Q <sub>gs</sub>	Gate-Source Charge		--	4.1	--	nC
Q <sub>gd</sub>	Gate-Drain Charge		--	7.1	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current	--	--	14	--	A
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current	--	--	40	--	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>F</sub> = 7.5A	--	0.9	1.5	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>F</sub> = 7.5A dI <sub>F</sub> /dt = 100A/µs	--	345	--	ns
Q <sub>rr</sub>	Reverse Recovery Charge		--	4.5	--	µC

**NOTES:**

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2. I<sub>AS</sub>=2.4A, V<sub>DD</sub>=50V, Starting T<sub>J</sub>=25°C
3. I<sub>SD</sub>≤13.6A, dI/dt ≤ 200A/us, V<sub>DD</sub> ≤ BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25 °C
4. Essentially Independent of Operating Temperature Typical Characteristics

# Typical Performance Characteristics

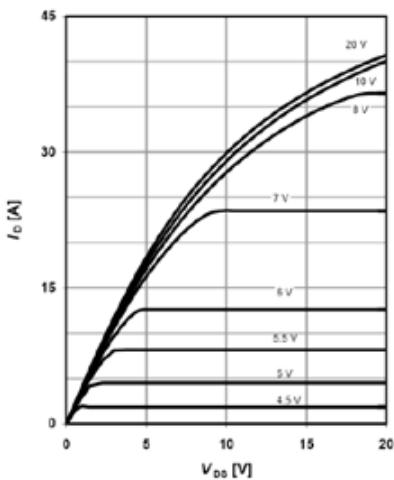


Figure 1: On-Region Characteristics@25°C

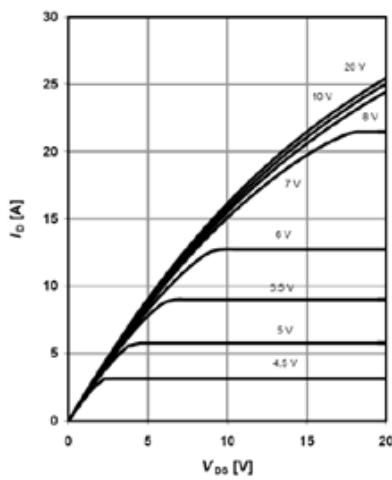


Figure 2: On-Region Characteristics@125°C

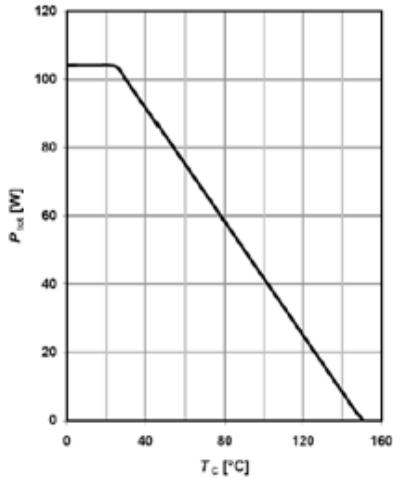


Figure 3:Power Dissipation

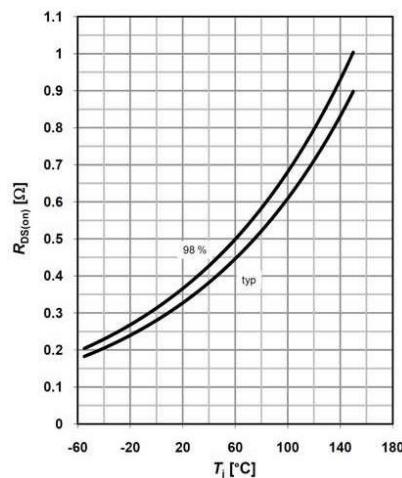


Figure 4: On-Resistance vs. Junction Temperature

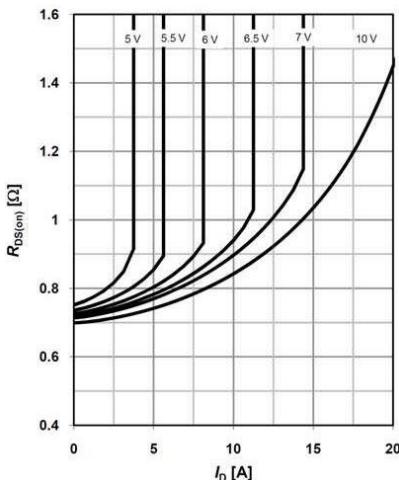
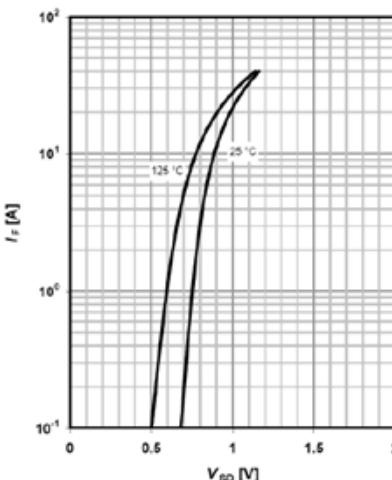
Figure 5: On-Resistance vs. Drain Current,  $T_j=125^\circ C$ 

Figure 6: Body-Diode Characteristics

# Typical Performance Characteristics

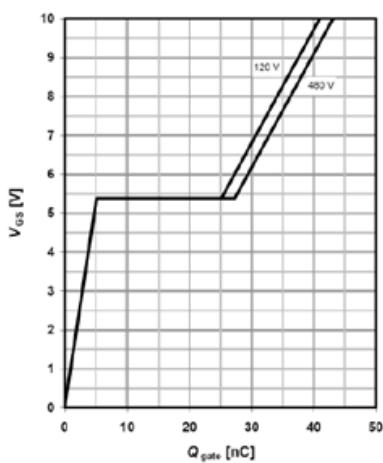


Figure 7 Gate-Charge Characteristics

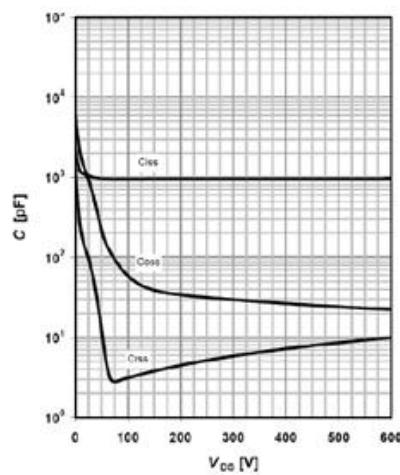


Figure 8: Capacitance Characteristics

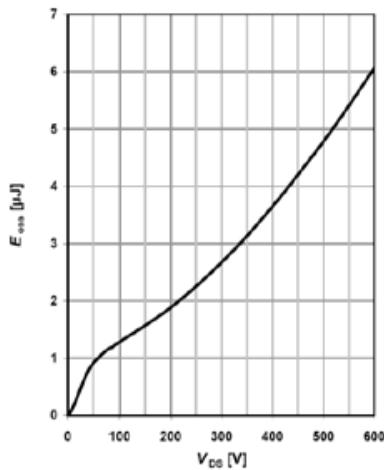
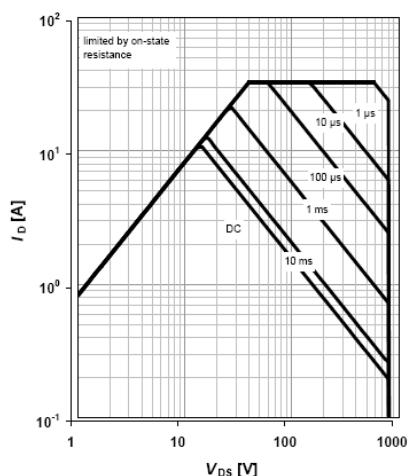
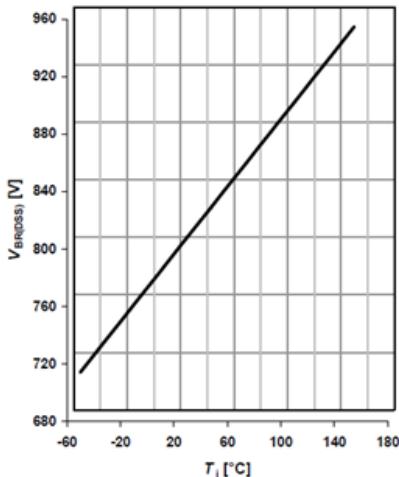
Figure 9:  $C_{oss}$  stored EnergyFigure 10: Maximum Forward Biased Safe Operating Area,  $T_c=25^\circ\text{C}$ 

Figure 11: Break Down vs. Junction Temperature

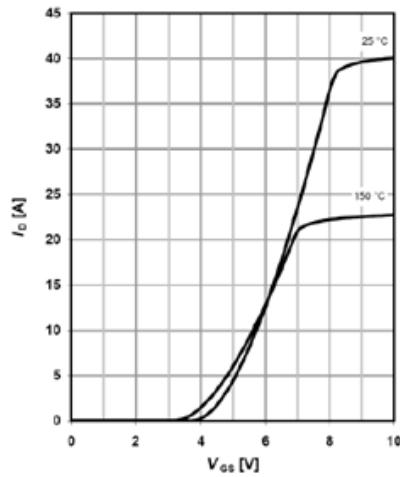


Figure 12: Typical transfer characteristics

## Typical Performance Characteristics

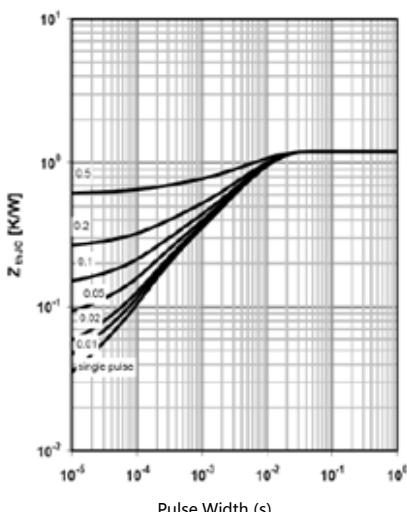


Figure 13: Maximum Transient Thermal Impedance

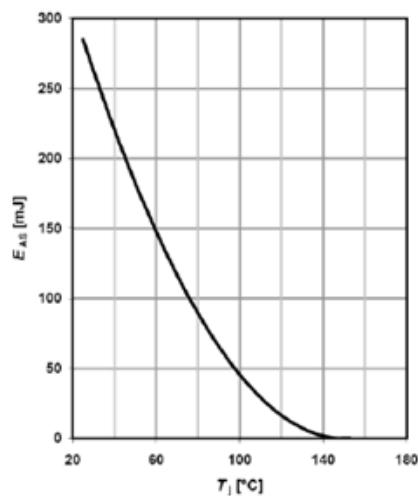


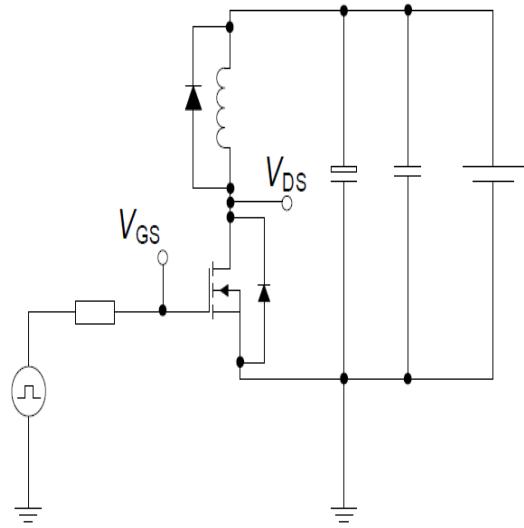
Figure 14: Avalanche energy

# Test circuits

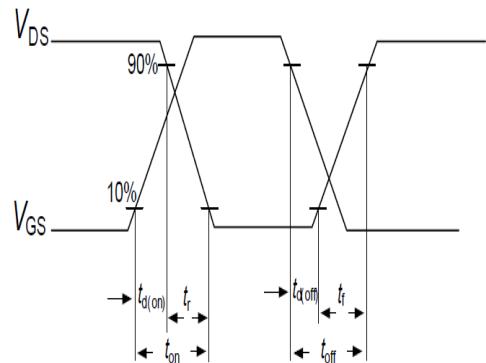
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## Switching times test circuit and waveform for inductive load

Switching times test circuit for inductive load

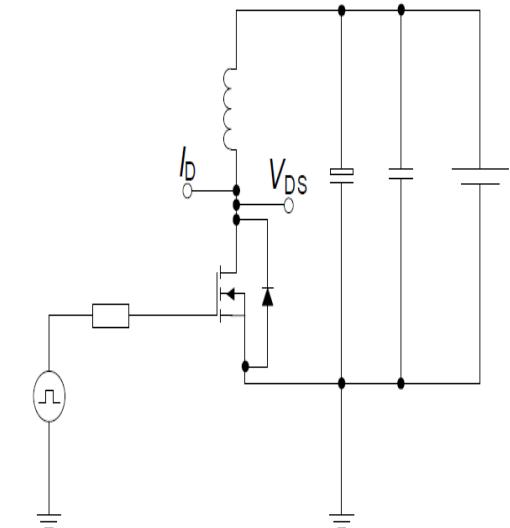


Switching time waveform

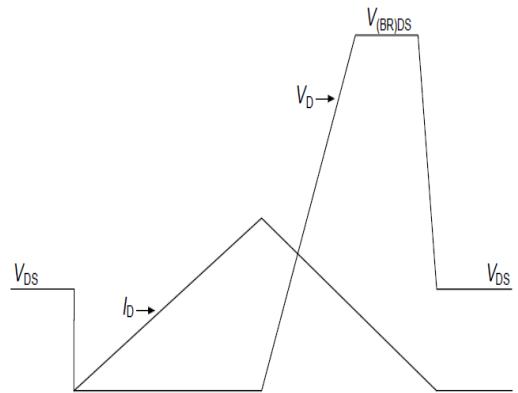


## Unclamped inductive load test circuit and waveform

Unclamped inductive load test circuit



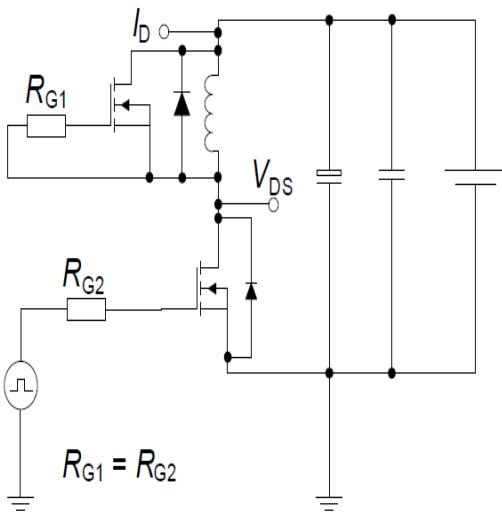
Unclamped inductive waveform



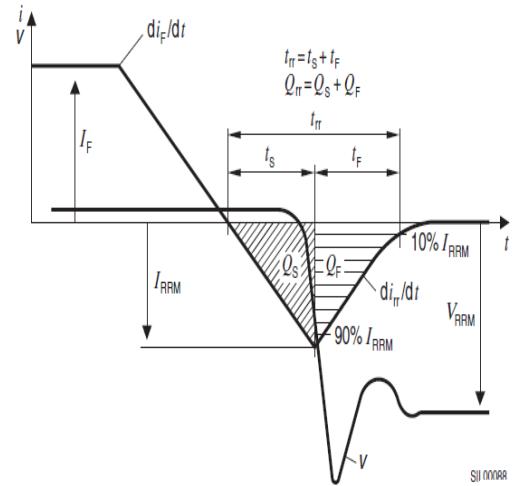
# Test circuits

## Test circuit and waveform for diode characteristics

Test circuit for diode characteristics

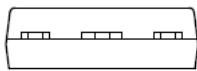
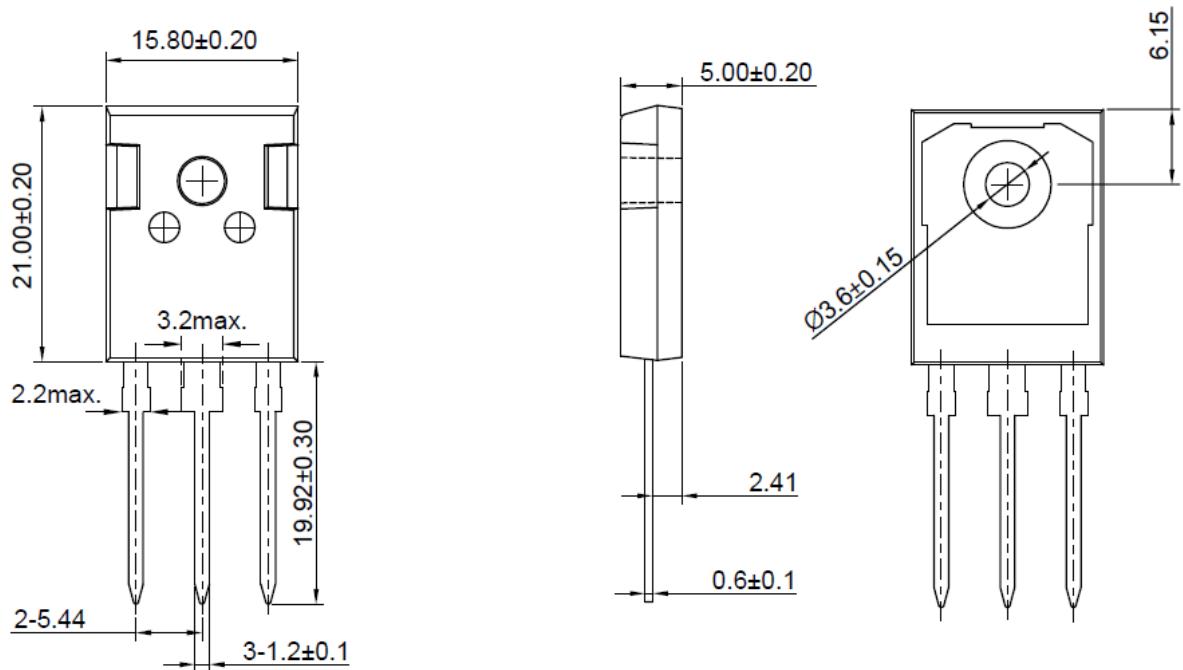


Diode recovery waveform



# Package Outline TO-247

TSK80R380S1 800V 13.6A N-Channel SJ-MOSFET



NOTES: 1. 表面粗糙度 Ra=1.14±0.20um.

2. 未标注公差 ± 0.15